

Supporting Information

Inherent Area-Selective Atomic Layer Deposition of ZnS

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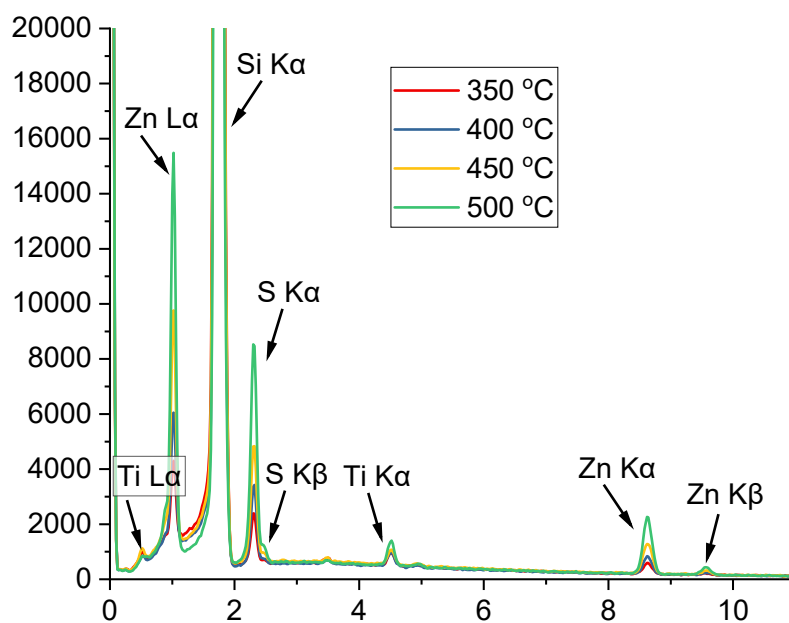


Figure S1: EDX spectra for the ZnS films that were deposited on Ti at 350, 400, 450, and 500 °C.

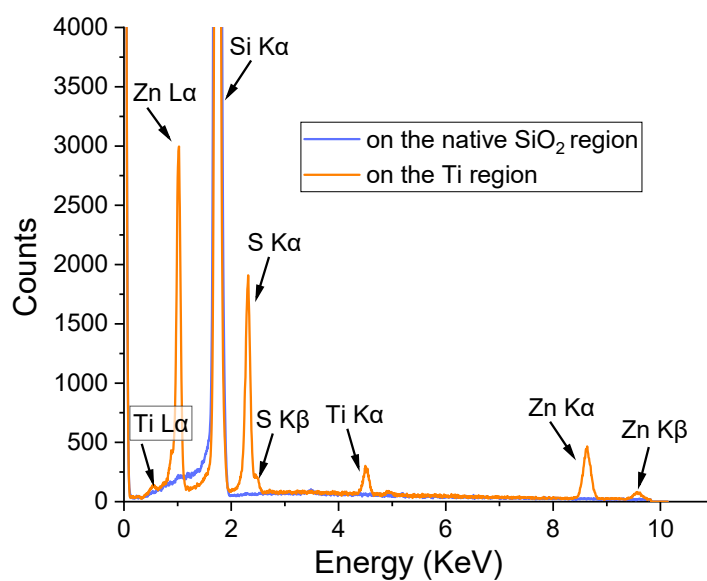


Figure S2: EDX spectra measured on the Ti and native SiO₂ regions on the Ti/native SiO₂ patterns after the ZnS deposition.